

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/790,149	CHEN, JINZU
	Examiner	Art Unit
	Y Quach Lee	2875

Search Notes



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10/790,149

Examiner

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**Applicant(s)/Patent under
Reexamination**

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SEARCHED

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner